

Session S4b

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A Low-Power MTJ-Based Nonvolatile FPGA Using Self-Terminated Logic-In-Memory Structure

Daisuke Suzuki¹ and Takahiro Hanyu²



¹Frontier Research Institute for Interdisciplinary Sciences, Tohoku University, JAPAN
<http://www.fris.tohoku.ac.jp/fris/index.html>

²Laboratory for Brainware Systems, Tohoku University, JAPAN
<http://www.ngc.riec.tohoku.ac.jp>

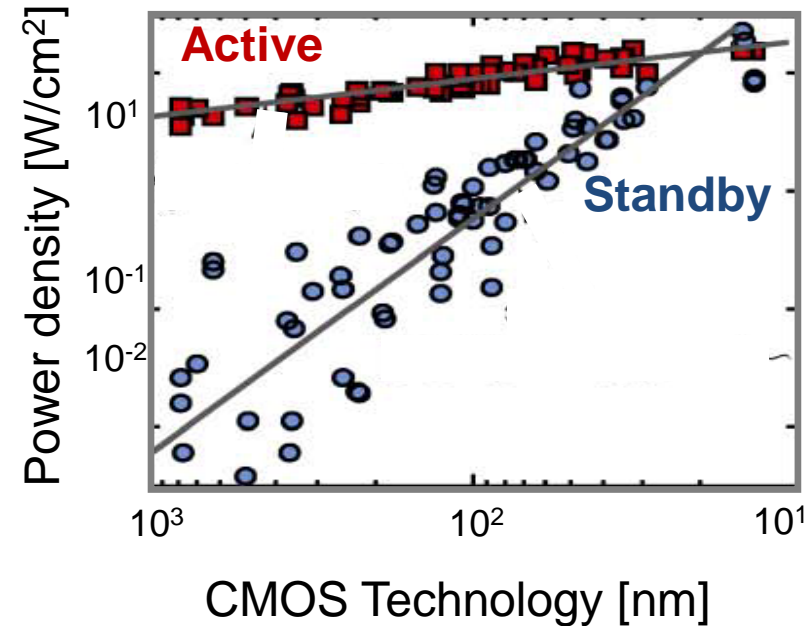
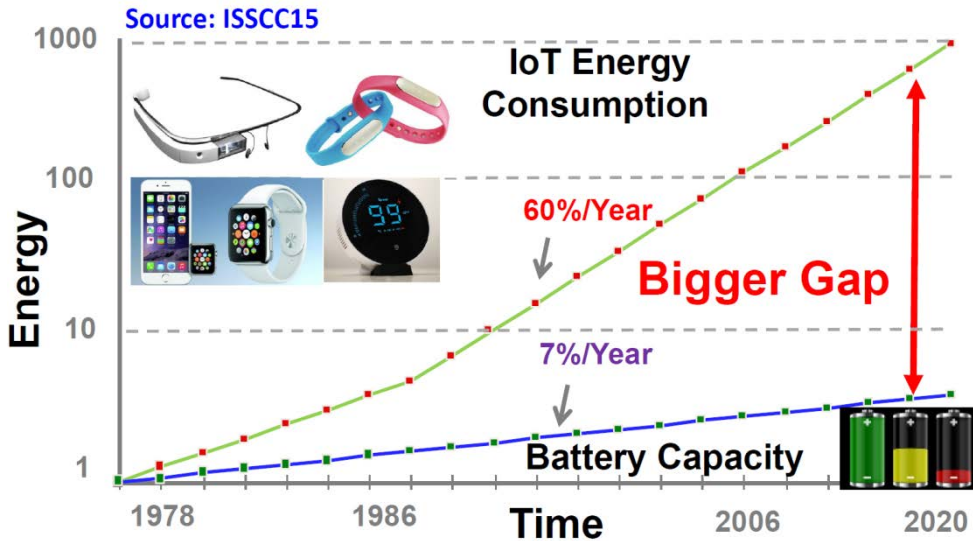
[Acknowledgement]

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A part of this research is supported by CIES consortium program.

Background

■ FPGA (Field-Programmable Gate Array)

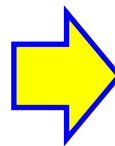
→ Various digital systems are implemented with short design time and low cost.



[Ref.] Y. Liu, et al., ISSCC, pp. 84-85, Feb. 2016.

[Ref.] E. Pop, Nano Res. 3 (2010) 147.

A large number of HW components are embedded for reconfigurability

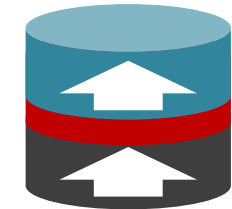
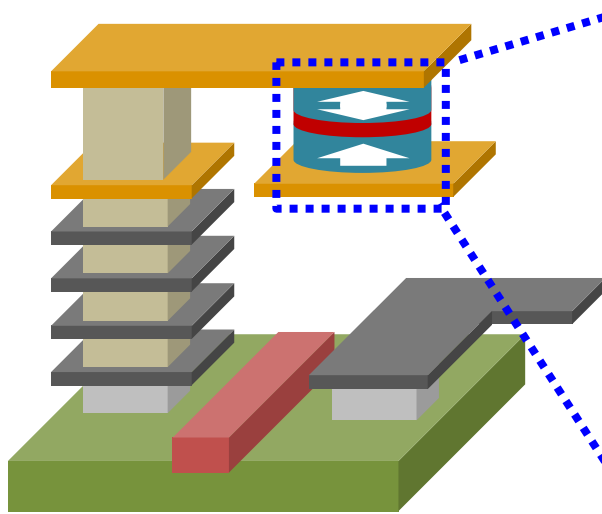


Large amount of **standby power** due to nano-scale CMOS process

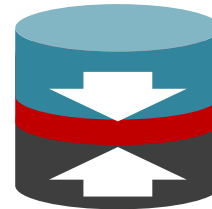
⇒ Low area & energy efficiency

How to overcome standby power problem of FPGA?

MTJ Device



R_P
(Low res.)



R_{AP}
(High res.)

- High endurance
- Scalability
- CMOS compatibility
- 3D-stacking

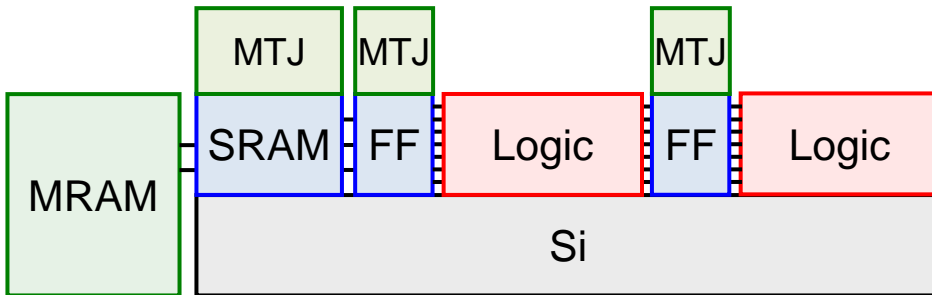
Storage element	SRAM	ReRAM device	Atom switch	CAAC-IGZO	MTJ device
Nonvolatile	No	Yes	Yes	Yes	Yes
Scalability	+	++	++	--	++
Endurance	++	-	--	+	++
Write access	++	+	-	+	++

MTJ device is the best candidate for realizing nonvolatile logic.

MTJ-Based Nonvolatile Logic Families

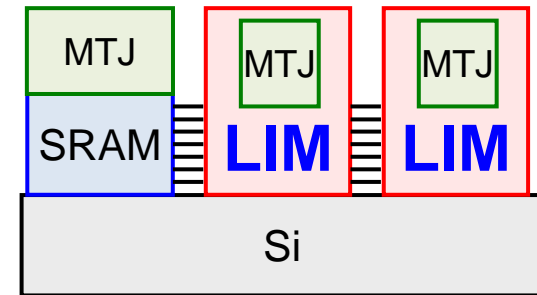
1st Generation

Storage elements are replaced by nonvolatile ones.

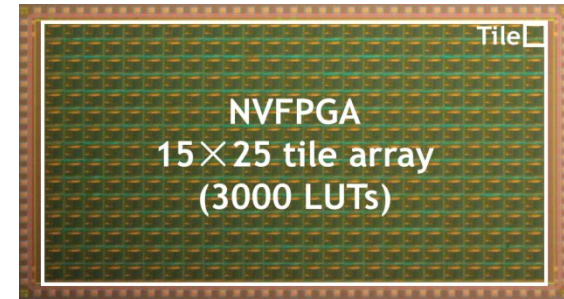
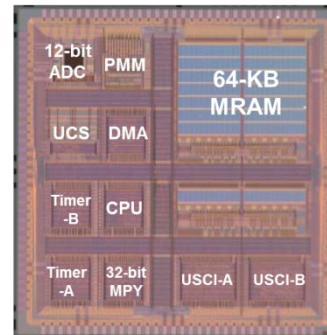
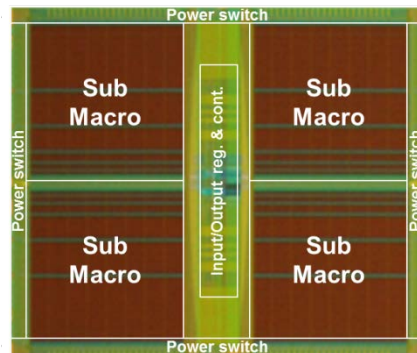
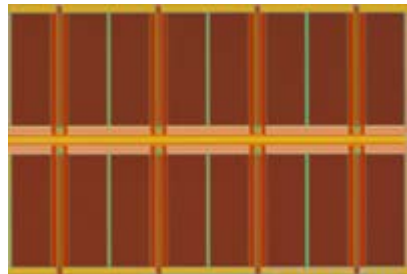


2nd Generation

Storage and logic functions are merged.
 → **Logic-in-memory (LIM) structure**



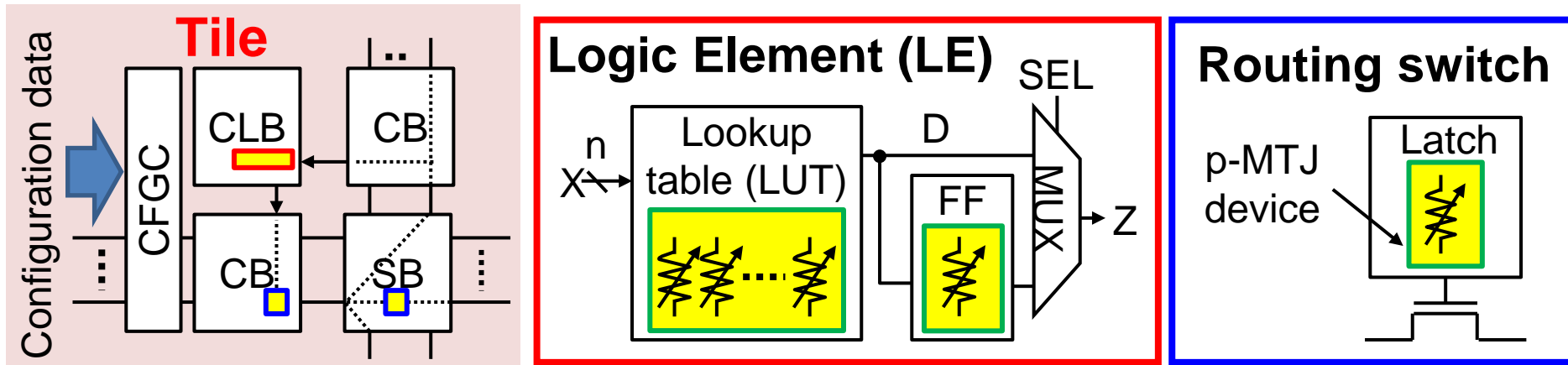
JSPS FIRST program (Leader Prof. H. Ohno)



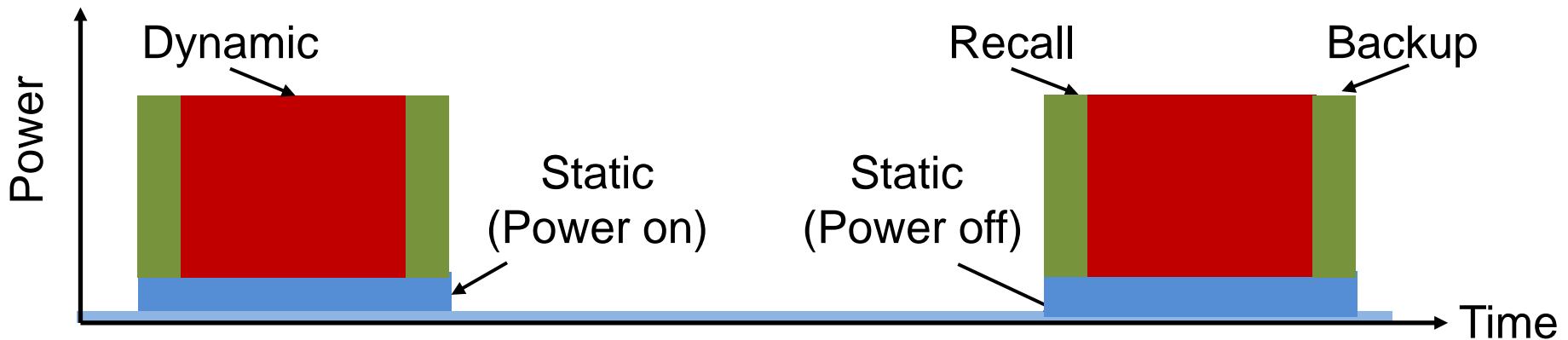
T. Ohsawa, et al., VLSIC, 2013. S. Matsunaga, et al., VLSIC, 2013. N. Sakimura, et al., ISSCC, 2014. D. Suzuki, et al., VLSIC, 2015.

MTJ device is the best candidate for realizing Nonvolatile logic LSI.

Design Issue

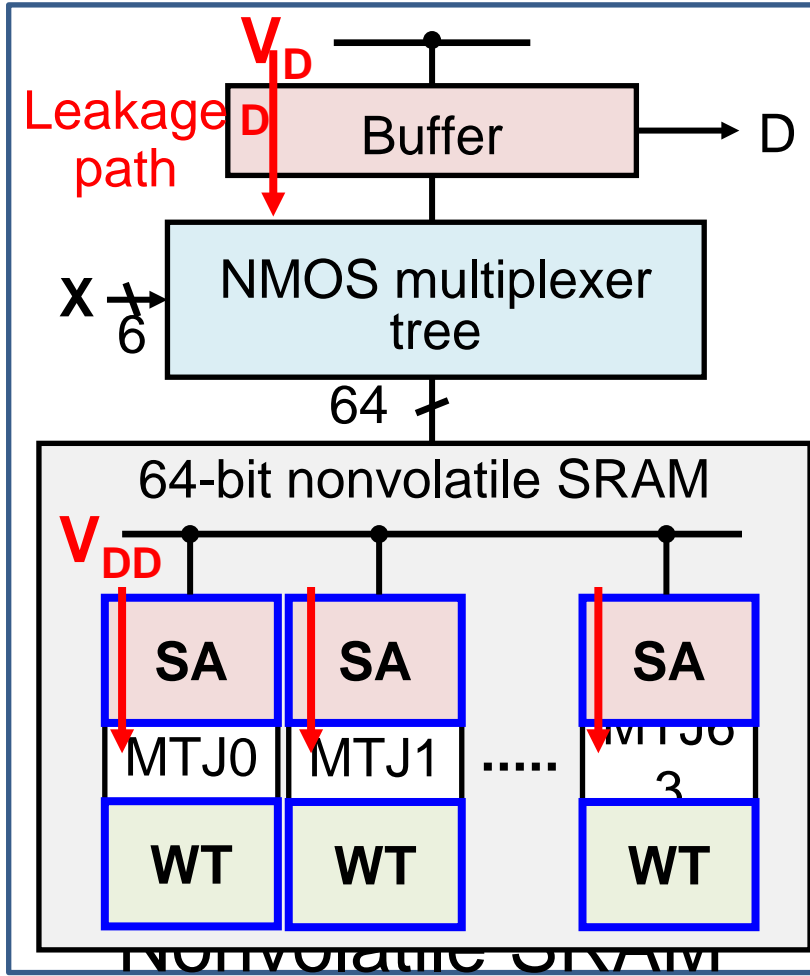


CLB: Configurable logic block CB: Connection block SB: Switch block CFGC: Configuration circuit

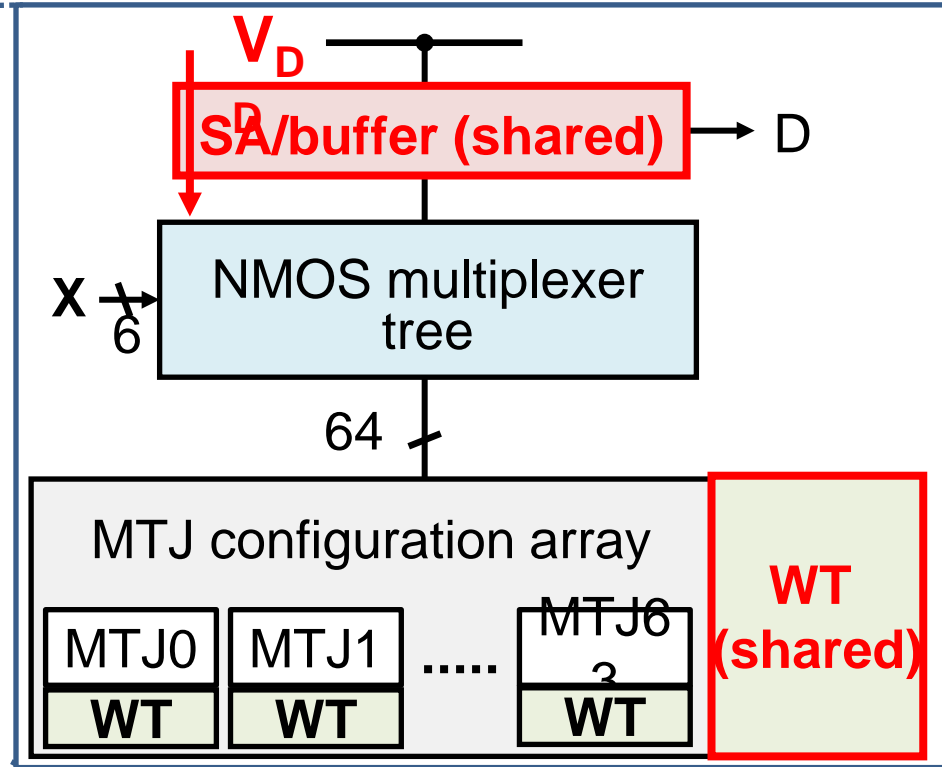


1. Reduction of the overhead due to recall/backup operations
2. Reduction of the number of leakage current paths

Logic-In-Memory Structure



based

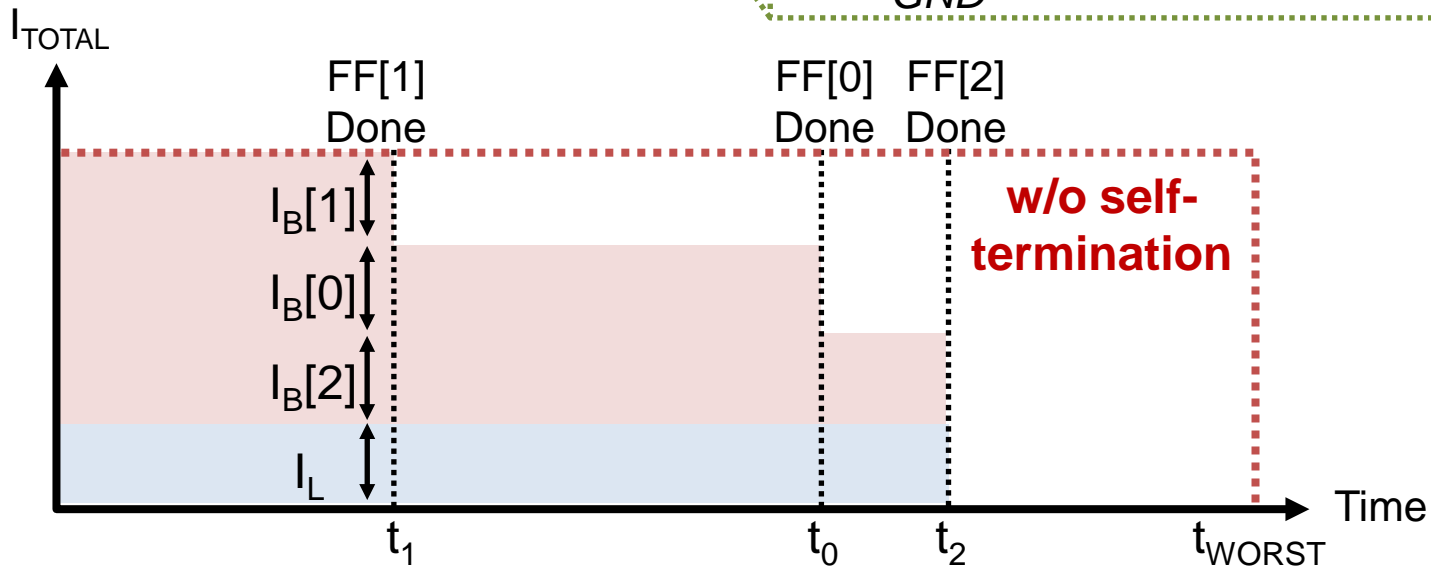
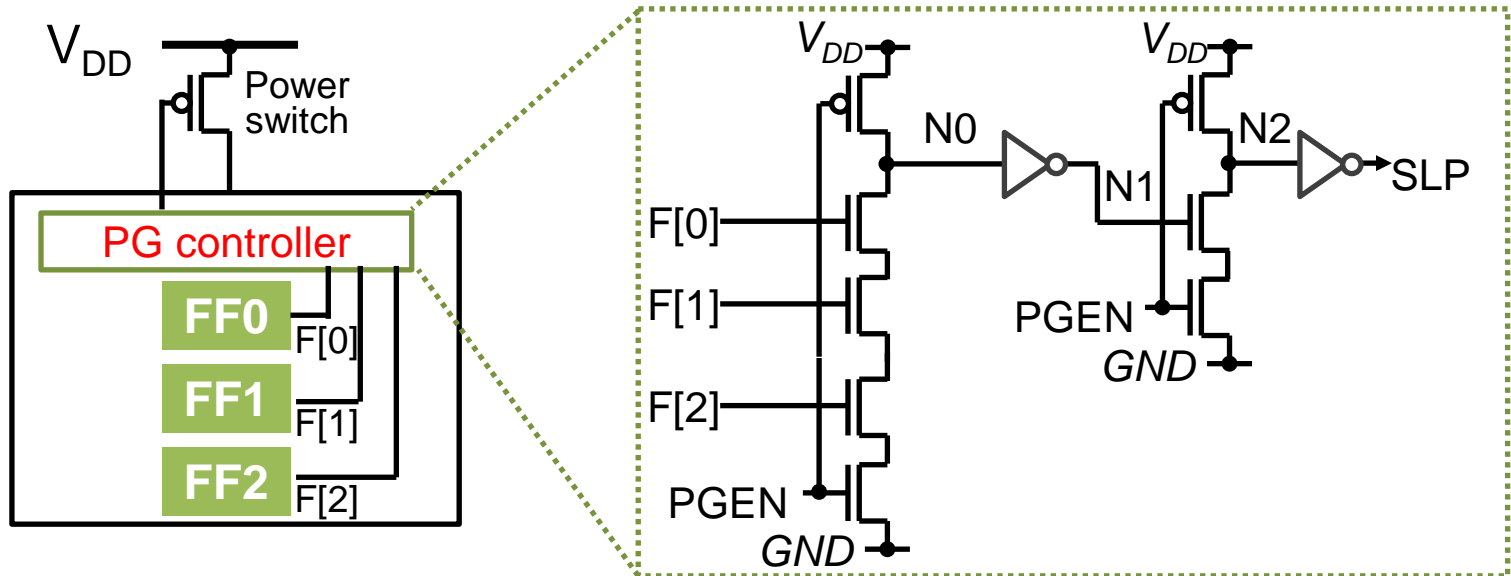


SA: Sense amplifier WT: Write transistor
Both **SAs** and **WDs** are **shared**.

Proposed

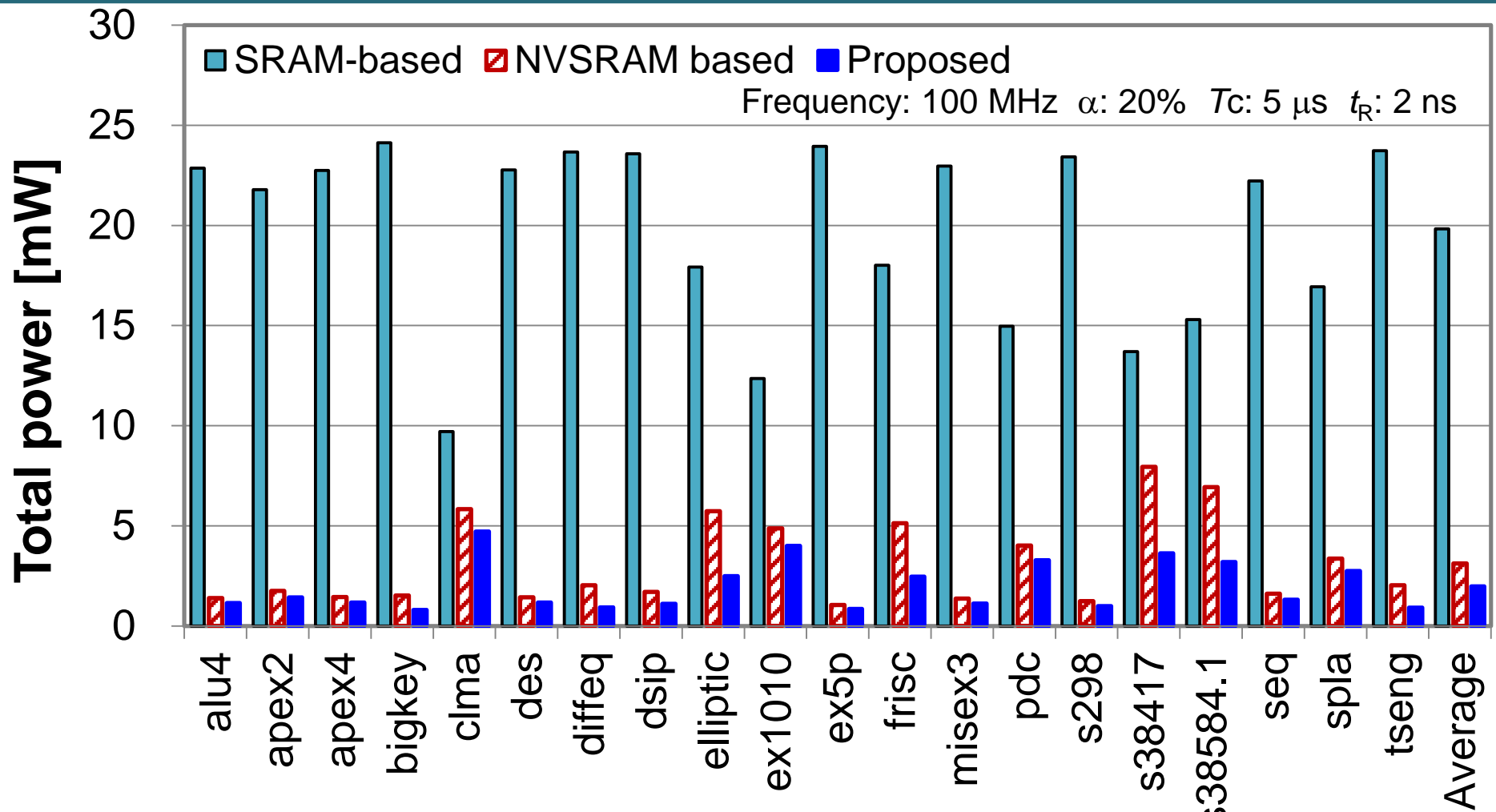
Compact circuitry with small number of leakage current paths

Self-Terminated Power-Gating Scheme



Minimization of both backup energy and leakage energy.

Evaluation



	SRAM-based	NVSRAM based	Proposed
Average total power	19.8mW	3.12 mW	1.97 mW

Thank you!